Supporting Information

Dark Current Reduction Strategy *via* a Layer-by-Layer Solution Process for a High-Performance All-Polymer Photodetector

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Figure S1. (a) The semi-orthogonal relationship of PEDOT:PSS, PTzBI-Ph and N2200.

(b) The processing sequence of gradient bulk heterojunction device.



Figure S2. The normalized absorption and PL spectra of PTzBI-Ph, and the normalized absorption spectrum of N2200 in films.

	Average ^b (Best) Values @-0.1 V				
Configuration ^a	J _d	EQE _{max}	R _{max}	$D^*_{\max}{}^c$	
	/nA cm ⁻²	/%	/A W ⁻¹	$/\times 10^{12}$ Jones	
PTzBI-Ph (60 nm)	7.37 ± 2.17	52.20 ± 3.58	0.23 ± 0.02	5.00 ± 1.23	
/N2200 (60 nm)	(3.74)	(55.50)	(0.25)	(7.22)	
PTzBI-Ph (80 nm)	5.68 ± 2.36	56.43 ± 2.06	0.25 ± 0.01	6.37 ± 1.58	
/N2200 (40 nm)	(2.35)	(54.48)	(0.25)	(0.90)	
PTzBI-Ph (80 nm)	3.77 ± 2.87	55.31 ± 2.34	0.25 ± 0.01	9.07 ± 4.05	
/N2200 (60 nm)	(1.25)	(53.15)	(0.25)	(12.54)	
PTzBI-Ph (80 nm)	3.22 ± 1.37	44.92 ± 6.30	0.21 ± 0.01	6.99 ± 1.73	
/N2200 (80 nm)	(1.24)	(42.04)	(0.20)	(9.82)	
PTzBI-Ph (100 nm)	3.51 ± 2.02	33.52 ± 6.00	0.15 ± 0.03	5.08 ± 1.34	
/N2200 (60 nm)	(1.30)	(26.14)	(0.13)	(6.21)	
PTzBI-Ph:N2200	75.97 ± 45.96	8.89 ± 0.12	0.04 ± 0.01	0.32 ± 0.10	
(2:1wt, 80 nm)	(29.68)	(9.02)	(0.044)	(0.45)	
PTzBI-Ph:N2200	10.46 ± 8.14	14.06 ± 0.59	0.06 ± 0.01	1.31 ± 0.42	
(2:1wt, 100 nm)	(5.08)	(14.72)	(0.067)	(1.65)	
PTzBI-Ph:N2200	6.74 ± 4.56	7.11 ± 0.74	0.04 ± 0.01	0.89 ± 0.34	
(2:1wt, 120 nm)	(3.13)	(7.31)	(0.037)	(1.17)	

Table S1. Performance of LBL and blend-processed OPDs with various thickness configurations.

^{*a*} The thickness of N2200 was estimated from difference value between total thickness and thickness of PTzBI-Ph.

^{*b*} Each value is the average of 8 devices.

^{*c*} Calculated from equation (1), 1 Jones = 1 cm Hz^{1/2} W⁻¹.



Figure S3. The EQE of all polymer photodetector with configuration of ITO/PEDOT:PSS (10 nm)/PTzBI-Ph (80 nm)/N2200 (60 nm)/Ca (5 nm)/Al (200 nm) and CsI (Tl)-based scintillator's emission spectrum.



Figure S4. (a) The *J-V* and (b) EQE characteristics of champion device before and after 160 days ageing.

PTzBI-Ph (80 nm) /N2200 (60 nm) ^a	Average ^b (Best) Data @-0.1 V			
	$J_{\rm d}$ /nA cm ⁻²	EQE _{max} /%	$R_{\rm max}$ /A W ⁻¹	$D^*_{\max}{}^c$ /×10 ¹² Jones
Fresh	3.77 ± 2.87	55.31 ± 2.34	0.25 ± 0.01	9.07 ± 4.05
	(1.25)	(53.15)	(0.25)	(12.54)
After 160 days	7.25 ± 5.60	46.63 ± 3.73	0.22 ± 0.02	5.56 ± 2.50
	(2.25)	(49.17)	(0.24)	(8.79)

Table S2. Performance of LBL-processed OPDs before and after 160 days stored in ambient and at room temperature.

^{*a*} The thickness of N2200 was estimated from difference value between total thickness and thickness of PTzBI-Ph.

^{*b*} Each value is the average of 8 devices.

^{*c*} Calculated from equation (1), 1 Jones = 1 cm Hz^{1/2} W⁻¹.